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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2721

Examiner: Unknown

Applicant : S. WAKASHIRO et al.

Serial No : 09/407,855

Filed: September 29, 1999

For : TARGET FOR PHOTOGRAMMETRIC ANALYTICAL MEASUREMENT

SYSTEM

## INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents and Trademarks Washington, DC 20231

Sir:

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In accordance with the duty of disclosure under 37 C.F.R. 1.56, 1.97-1.98, Applicants hereby bring the following documents to the attention of the Examiner:

U.S. Patent 5,699,444 to PALM, issued December 16, 1997;

Japanese Patent Document JP 10-170263, published June 26, 1998. Applicants will submit an English translation thereof shortly;

Japanese Patent Document JP 7-174563, published July 14, 1995, and an English translation thereof;

Japanese Patent Document JP 9-113224, published May 2, 1997, and an English translation thereof; and

Japanese Patent Document JP 6-241798, published September 2, 1994, and an English

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translation thereof.

Applicants respectfully request that the Examiner consider and cite these documents. Copies of the above-noted documents are attached and have been listed on a PTO-1449 Form which is also attached hereto. Accordingly, the Examiner is requested to initial the appropriate spaces on the attached PTO-1449 Form and to return a copy of the form to the Applicants with the next official communication in the present application to confirm consideration of these documents.

Should there be any questions, the Examiner is invited to contact the undersigned attorney at the number listed below.

Respectfully submitted, S. WAKASHIRO et al.

(h) les ls. 26,715

Bruce H. Bernstein

Reg. No. 29,027

December 29, 1999 GREENBLUM & BERNSTEIN, P.L.C. 1941 Roland Clarke Place Reston, VA 20191 (703) 716-1191